# Silicon Isotope Separation by Infrared Free Electron Laser

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S ilicon isotope separation through irradiation of Si2F6 using an infrared free-electron-laser (FEL) in the 800 cm<sup>-1</sup> and 1000 cm<sup>-1</sup> regions was examined. By controlling the laser wavenumber, preferential decomposition of Si<sub>2</sub>F<sub>6</sub> into SiF4 and SiF2, enriched with <sup>29</sup>Si and <sup>30</sup>Si isotopes, was induced.

Key words: silicon, isotope separation, infrared free electron laser, Si<sub>2</sub>F<sub>6</sub>.

## **1. INTRODUCTION**

Silicon consists of three stable isotopes: <sup>28</sup>Si, <sup>29</sup>Si and <sup>30</sup>Si. By controlling the isotope ratio, the thermal and nuclear properties of silicon can be improved [1]. A single crystal of <sup>28</sup>Si is predicted to have a high thermal conductivity due to the absence of isotope scattering by other isotopes [2]. SiC consisting of <sup>29</sup>Si and <sup>30</sup>Si is an attractive candidate as a material with low inducedradio-activation in high energy neutron irradiation environments [1]. Enrichment with <sup>30</sup>Si is advantageous in the production of n-type semiconductor doped with phosphor by neutron transmutation doping [3]. To realize such isotopically controlled silicon, a practical isotope separation process is required. Laser isotope separation with infrared multi-photon decomposition is very attractive method of producing a large amount of isotopes. Recently, silicon isotope separation of  $Si_2F_6$ with a CO<sub>2</sub> infrared laser at 1000 cm<sup>-1</sup> was reported [4,5]. However, Si<sub>2</sub>F<sub>6</sub> has additional absorption peaks at around 400 and 800 cm<sup>-1</sup>. But, because of the limitations of CO<sub>2</sub> laser emission lines, it is not obvious that it is possible to achieve isotope separation with CO2 laser at these other infrared wavenumbers, while the free electron laser is tunable to these wavenumbers.

In the present paper, we study silicon isotope separation from  $Si_2F_6$  by using an infrared free electron laser (FEL), in paticular in the 800 and 960 cm<sup>-1</sup> regions.

#### 2. EXPERIMENTAL

The  $Si_2F_6$  used in these experiments was produced by fluorination of  $Si_2Cl_6$  with  $ZnF_2$ .  $Si_2F_6$  contained a trace of  $SiF_4$  impurities. After purification of the  $Si_2F_6$ , the final  $SiF_4$  impurity was 0.06 and 0.09 vol% for two lots of  $Si_2F_6$ .

Figure 1 shows a schematic of the experimental apparatus. The infrared FEL at the FOM Institute for Plasma Physics in the Netherlands was used as a light source. The wavenumbers of the FEL were set at 786-814 and 950-972 cm<sup>-1</sup>. A laser pulse consisted of 10 $\mu$ s macropulse with a 8.33-10Hz repetition frequency composed of 1 ns micropulses with a repition rate of 1 GHz. The beam diameter was 2 mm and the laser energy was 12-27 mJ in front of the reaction cell.



Fig. 1 Schematic of experimental apparatus.

The laser beam was focused by a ZnSe lens and introduced into a reaction cell. The reaction cell was a cylindrical Pyrex glass tube, 100 mm long, 10 mm in inner diameter, and equipped with KCl windows at both ends. The flow rate and pressure of  $Si_2F_6$  were set at 8.3 mm<sup>3</sup>s<sup>-1</sup> and 13.3 Pa. The irradiation was performed for 300 s at room temperature and decomposed the  $Si_2F_6$  into  $SiF_4$  gas and  $SiF_2$  polymer. Both product  $SiF_4$  and residual  $Si_2F_6$  were captured with a liquid nitrogen cold trap and then separated into each component through low temperature distillation. The isotope ratios were determined by using a quadrupole mass spectrometer from the relative ion intensities of the isotope species.

### 3. RESULTS AND DISCUSSION

Figure 2 shows the infrared absorption spectrum of natural  $Si_2F_6$  in the region of 700-1100 cm<sup>-1</sup>. There are strong absorption peaks at 990 and 820 cm<sup>-1</sup> [6,7]. The peak at 990 cm<sup>-1</sup> is due to an asymmetric stretching vibration, and the peak at 820 cm<sup>-1</sup>, to a symmetric vibration of the Si-F bond. Since the natural abundance ratio of silicon is <sup>28</sup>Si:<sup>29</sup>Si:<sup>30</sup>Si = 92.23:4.67:3.10, these peaks are attributed to the vibration of Si<sub>2</sub>F<sub>6</sub> molecules containing <sup>28</sup>Si. Though the spectral lines for <sup>29</sup>Si and <sup>30</sup>Si are not apparent in this figure, they should be present around 990 and 820 cm<sup>-1</sup> [8]. Since the emission of the FEL covers these ranges, infrared multi-photon decomposition of Si<sub>2</sub>F<sub>6</sub> molecules into products

containing <sup>29</sup>Si and <sup>30</sup>Si can occur effectively by selecting the appropriate wavenumber. The reaction producing SiF<sub>4</sub> by infrared multi-photon decomposition is assumed to be



Fig. 2 Infrared spectrum of  $Si_2F_6$  around 700 to 1100 cm<sup>-1</sup>.



Fig. 3 Enrichment factor of Si in the product  $SiF_4$  as a function of wavenumber around 960 cm<sup>-1</sup>.



Fig. 4 Enrichment factor of Si in the product  $SiF_4$  as a function of wavenumber around 800 cm<sup>-1</sup>.

Figure 3 shows the enrichment factor of Si in the product SiF<sub>4</sub> as a function of wavenumber around 960 cm<sup>-1</sup>, where the enrichment factor  $\beta^i$  is defined as

$$\beta^{i} = (\text{product }^{i}\text{SiF4})/(\text{natural }^{i}\text{SiF4})$$
 (2).

When  $Si_2F_6$  was irradiated around 950-972 cm<sup>-1</sup>, the product  $SiF_4$  was enriched with <sup>29</sup>Si and <sup>30</sup>Si.  $\beta^{29}$  has a peak value of 3.8 at 962.5 cm<sup>-1</sup> and  $\beta^{30}$ , of 5.7 at 956.9 cm<sup>-1</sup>. These  $\beta$  values show that the product  $SiF_4$  is composed 17.7% of <sup>29</sup>Si and 17.7% of <sup>30</sup>Si.

Figure 4 shows the enrichment factor of Si isotopes in the product SiF<sub>4</sub> as a function of wavenumber around 800 cm<sup>-1</sup>. <sup>29</sup>Si was enriched in the product SiF<sub>4</sub> between 786-814 cm<sup>-1</sup>.  $\beta^{29}$  has a peak value of 1.2 at 801.3 cm<sup>-1</sup>, while  $\beta^{30}$  is smaller than 1 for all wavenumbers. The difference of  $\beta^{30}$  between the 960 cm<sup>-1</sup> region and the 800 cm<sup>-1</sup> region is probably due to the difference of the vibration modes of the Si<sub>2</sub>F<sub>6</sub> molecules in the two regions.



Fig. 5 The infrared spectrum of  $Si_2F_6$  (right axis), the FEL enrichment factors, and the  $CO_2$  laser enrichment factors.

Figure 5 shows the infrared spectrum of  $Si_2F_6$  (right axis), the FEL enrichment factors, and the CO<sub>2</sub> laser enrichment factors. The FEL data are the same as those in Figure 3, and the CO<sub>2</sub> laser data are from our previous study that was performed under the same experimental conditions but using a CO<sub>2</sub> pulse laser [9]. Since there is only a small emission gain for the CO<sub>2</sub> laser at 956-965 cm<sup>-1</sup>, the pulse energy was not large enough to decompose the Si<sub>2</sub>F<sub>6</sub>, so there is no data in that region, while the FEL can emit continuously in that region, producing a  $\beta^{29}$  enrichment peak at 962 cm<sup>-1</sup>. Compared to CO<sub>2</sub> laser results, the enrichment factor of FEL is relatively low. This can be attributed to two features of the FEL pulse: the spectral width,  $\delta\lambda/\lambda$ , and the macropulse length. The Spectral width and the macropulse length of the FEL are 1-2% and 10 µs

respectively, whereas those of the  $CO_2$  laser are 0.003% and 104 ns, respectively. The broad spectral width and long pulse width probably contribute to the lower isotope selectivity of the FEL.

## 4. CONCLUSION

The isotope separations of  $^{29}$ Si and  $^{30}$ Si were made using the isotope selective infrared multi-photon decomposition of Si<sub>2</sub>F<sub>6</sub> by infrared the FEL irradiation.

A relatively high enrichment of  $^{29}$ Si and  $^{30}$ Si in the product SiF<sub>4</sub> was observed for laser irradiation in the range 950-972 cm<sup>-1</sup>.

For the first time, enrichment of  $^{29}$ Si at around 800 and 960 cm<sup>-1</sup> has been achieved, by using an FEL rather than a CO<sub>2</sub> laser.

The low enrichment factor for the FEL compared to the  $CO_2$  laser is probably due to the broader spectrum width and longer pulse width of the FEL.

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